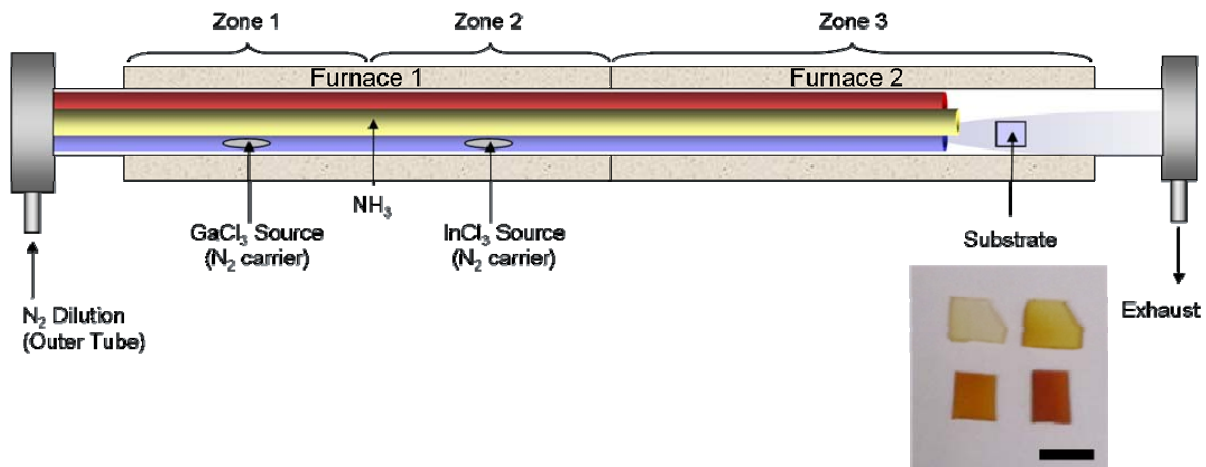


# Epitaxial Growth of InGaN Nanowire Arrays for Light Emitting Diodes

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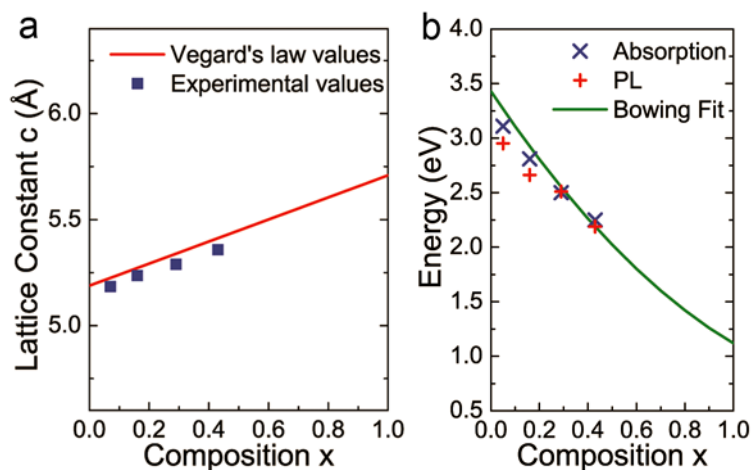
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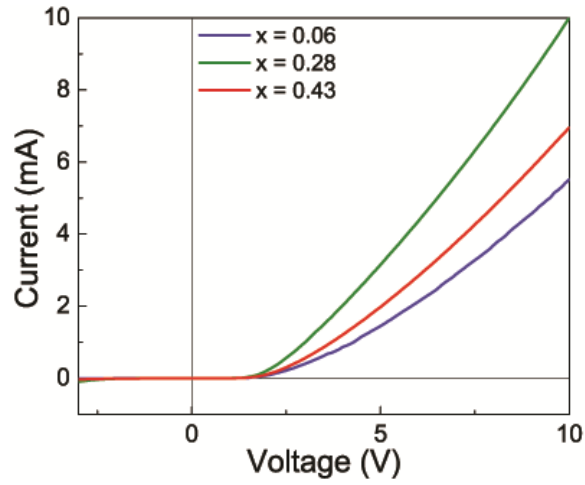


**Figure S1.** Schematic of the three-zone HCVD system. This system has three 1/4-inch quartz tubes housed in a 1-inch quartz tube situated within two furnaces equipped with three independently controlled thermocouples (zones 1-3). The system supplies GaCl<sub>3</sub> (N<sub>2</sub> carrier), InCl<sub>3</sub> (N<sub>2</sub> carrier), and

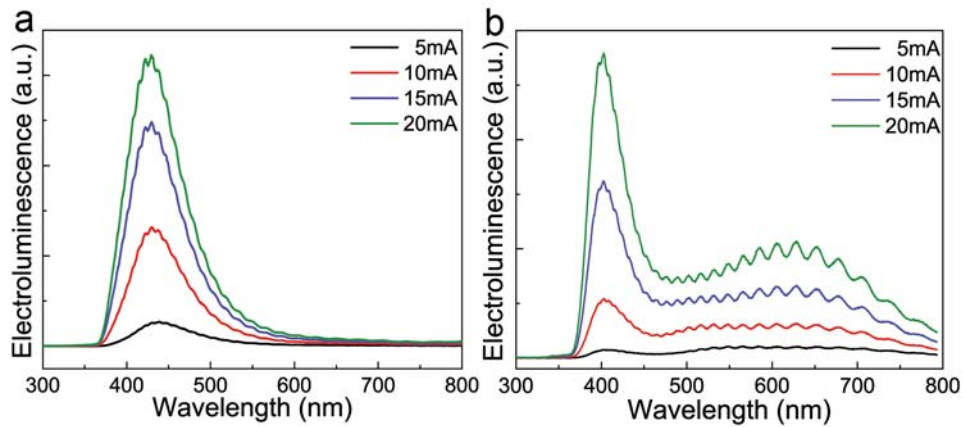
NH<sub>3</sub> precursors through two inner tubes (blue, yellow). GaCl<sub>3</sub> and InCl<sub>3</sub> were placed in the same inner tube and spaced apart such that the vapor pressures of each precursor could be independently controlled in zone 1 (GaCl<sub>3</sub>) and zone 2 (InCl<sub>3</sub>). N<sub>2</sub> gas also flows through the outer tube during the reaction. The photograph in the inset shows four homogeneous samples of different indium compositions. Scale bar = 6 mm.



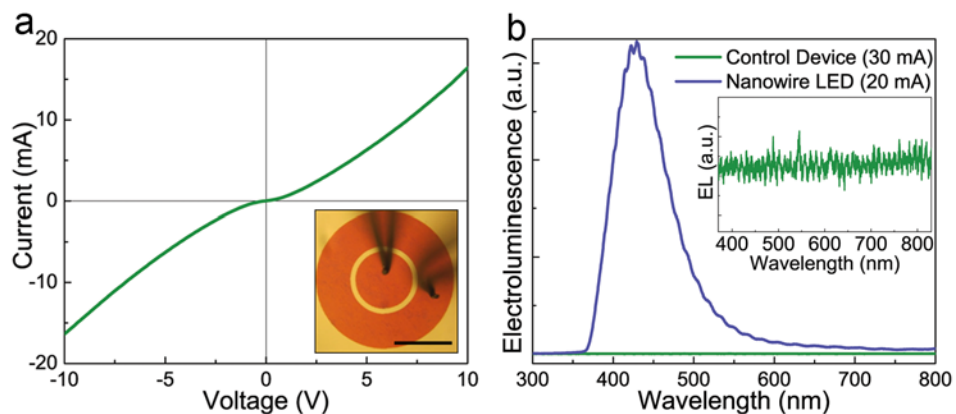
**Figure S2.** Vegard's law and energy correlations for  $\text{In}_x\text{Ga}_{1-x}\text{N}$  nanowire arrays. (a) The (002) wurtzite peak of the XRD patterns was analyzed to obtain the lattice constant  $c$  and was correlated to its EDS composition. The straight line represents the Vegard's law correlation between GaN ( $c = 5.188 \text{ \AA}$ ) and InN ( $c = 5.709 \text{ \AA}$ ). (b) The square of absorption plots was linearly extrapolated to determine the bandgap energy of different compositions. The black bowing line represents the fitting equation used by Kuykendall *et al.* Corresponding PL peak energies show a slight Stokes shift in emission from the band gap.



**Figure S3.** Overlaid I-V curves for  $x = 0.06$ ,  $x = 0.28$ , and  $x = 0.43$  showing rectification.



**Figure S4.** The emission's dependence on current for the (a)  $x = 0.06$  and (b)  $x = 0.43$  LED devices. (a) The spectra for the  $x = 0.06$  device show an 8 nm blue shift with increasing injection current. (b) The spectra for the  $x = 0.43$  device show no noticeable blue shift with increasing injection current.



**Figure S5.** Control device showing no emission from the substrate. Ni/Au (20 nm / 20 nm) contacts were deposited on the p-GaN substrate in a geometry that mimicked the current injection geometry used in the LED devices. (a) I-V curve of the control device. Inset: Photograph of the measured device. Scale bar = 250  $\mu\text{m}$ . (b) Corresponding spectrum (green) of the device sourced with 30 mA of injection current showing no emission from the p-GaN/undoped-GaN junction. For comparison, the EL spectrum (blue) from the forward-biased  $x = 0.06$  LED device is shown with the control device's spectrum. Inset is a close-up view of the control device's spectrum showing only background noise.